



The Nanofinder® 30:

A 3-D Raman Microscopy System
Micro/Nano Scale
Microspectroscopy

3-dimensional imaging and chemical
analysis—*simultaneously*

The world's most advanced
nanotechnology instrument—high
sensitivity, high spatial resolution,
easy to operate.

More than 10 x improvement in sensitivity
Enhanced mechanical and optical stability

- **New optical system with greater than 10X increase in sensitivity over our previous generation instrument.**

Previously undetectable signals are now visible. Higher sensitivity allows faster analysis and the use of low power (sub-mW) lasers for non-destructive analysis.

- **Rugged and highly stable mechanical and optical mounting.**

By combining technology from analytical instrumentation and laser resonators, 3D optical nanometer scale measurements are made with negligible mechanical drift.

- **Applicable to SERS and near field optical microscopy**

In cooperation with the Kawada Research Laboratory at Osaka University we are developing a system targeting 30 nm spatial resolution (currently 80 nm). Confocal microscopy spatial resolution of 150 nm using 633 nm HeNe laser.

- **3D Raman and AFM: concurrent, congruent.**

This revolutionary technique allows 3D optical nano-scale spectroscopy and without relocating

the sample. Complete physical and spectral characterization in only a few minutes.

- **Polarization microscopy**
Equipped with polarizers in both excitation and detection channels.
- **Fully automated**
Simplified, reproducible setup with all functions under computer control. Automated laser output control, automated confocal pinhole setup.
- **Multiple laser input**
The standard configuration allows two different laser inputs, with optional hardware for up to five different excitation lasers.
- **Modular design with user selectable spectrometers/spectrographs**
The standard 520 mm spectrometer can be installed with 4 grating turret. Double monochromators, echelles or user supplied spectrometers can be installed.
- **Multifunction**
Raman, fluorescence, confocal microscopy, AFM topography, SERS (surface enhanced raman), imaging.

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